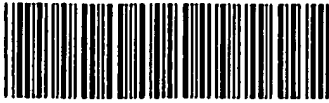


Search Notes



Application/Control No.

10/695,874

Examiner

Kin-Chan Chen

Applicant(s)/Patent under
Reexamination

HAYAMI ET AL.

Art Unit

1765

SEARCHED

Class	Subclass	Date	Examiner
438	706	7/18/05	K-CC
	710		
	712		
	714		
	719		
	723		
	725		
438	745		
510	175		
510	176		
134	1.1		
	1.2		
134	1.3	7/18/05	K-CC
updated		9/2/05	K-CC

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
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134	1.1		
134	1.2		
134	1.3	9/2/05	K-CC

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
Exact Key words search USPAT, US pub-pub. Epo, JPO, Derwent IBM - TOB.	7/17/05	K-CC
inventor search	7/15/05	K-CC
updated	9/2/05	K-CC